

# **Inverted Metallurgical Microscope with Image Analysis System**

## **Part I: Inverted Metallurgical Microscope (Imported Assembled)**

### **Model: SuXma-Met IB- I**

Inverted microscope equipped with **UIS System, Infinity Plan optics** for industrial and research applications having magnification range **100X to 1000X (Dry)**. Wide magnification range, high resolution optics, polarizer and analyzer facility, large working stage with high travel range makes it perfect tool for various industrial and material science research applications.

### **Specification**

#### **Optics**

**Eyepiece Pairs** - Wide field 10X, F. N. 22

**Objectives** - Infinity plan achromatic objectives

- PL L10X/0.25 working distance : 20.2 mm

PL L20X/0.40 working distance : 8.80 mm

PL L50X/0.70 working distance : 3.68 mm

PL L100X/0.85 (dry) working distance : 0.40 mm

#### **Nosepiece**

Objectives mounted on Quintuple, Backward ball bearing inner locating nosepiece with positive click stops. Durable, wide rubber grip on turret makes switching objectives fast and easy.

#### **Illumination**

- Koehler 6 volt / 30 watt halogen illumination, lamp housing with centering facility.
  - Full range intensity variation with conveniently placed knob.
  - Frosted Glass, Blue, green, and yellow filters included
- Integrated field diaphragm , aperture diaphragm  
puller type polarizer

#### **Head**

Binocular head is inclined 45° for easy use, with an interpupillary distance adjustment range of 53 to 75mm

#### **Photography Port**

C Mount port to adapt camera

#### **Focusing system**

Coaxial coarse/fine focus, with tension adjustable and up stop minimum division of fine focusing is 2µm.

#### **Stage**

Mechanical stage overall size: 242mmX200mm

Moving range : 30mmX30mm

Rotundity and rotatable stage size: maximal measurement is  $\Phi$ 130mm and minimal clear aperture is less than  $\Phi$ 12mm

## **Part II: Microstructure Image Analyzing System**

### **Model: DeXel-Metallography I**

## A. Hardware

### A.1 Digital Color Camera (5 Mpixel)

#### Make - German

Sr. No.	Description	Technical Specification
1	Image Sensor	2/3" type CMOS
2	Interface	USB 3.0 interface
3	Effective picture elements	2592 x 1944 (H x V)
4	Maximum Frame Rate	5.8 at high resolution
5	Pixel Size	3.4 X 3.4
6	Shutter Type	Global reset
7	Scanning Type	Progressive scan

### A.2 Camera adapter

Specially designed Camera adapter as per microscope photography port

## B. Software

### B.1 Grain size analysis

Measurement by 2 methods

#### c. Intercept Method (Manual / Automatic mode) as per E 112, E 930, E1382

Facility to select number and orientation of linear test lines

Facility to select concentric test circles

Facility to select minimum number of intercept lines depending upon number of intercepts found

Facility to find intercept length and ASTM Grain No. for individual grains

#### d. Planimetric Method

Facility for selection of region of interest for planimetric

method Color coding of grains as per ASTM size number

Grain size distribution with graphical plot and identification of largest grain available

#### - Auto grain boundary tracing, enhancing and grain cleaning feature for automatic analysis

- Pop-up alert for insufficient intercepts or grains in test region

### B.2 Phase Analysis as per ASTM E562

Automatic thresholding of the image

12 No. of phases can be determined simultaneously

Pick & place of gray value for smart selection of a phase of interest from rest of the matrix Histogram, Color coding for independent phases

Facility for selection of region of interest

#### **Manual Grid for measurement of multiple phases.**

### B.3 Inclusion Analysis as per ASTM E45, E1122, DIN 50602, JIS G 0555

Separation and rating as per ASTM E45, E1122, DIN 50602, JIS G 0555

Separation of superimposed inclusions (Sulphides superimposed over oxides) and rating them independently

Facility for edit and rectify manually

Provision to compile results for number of fields of view as per various standards

### **B.3A Inclusion analysis of as per ASTM Standard B796-02**

Nonmetallic Inclusion Content of Powders Intended for Powder Forging (PF) Applications

### **B.4 Cast Iron Analysis**

#### **a. Nodular Cast Iron as per ASTM E 2567-11(latest standard for Image Analyzer)**

Nodularity and nodule count as per As per ASTM E 2567-11

Size classification as per standard ASTM A 247 and estimation of percentage of each class

Size threshold facility to filtrate non-graphite particles

Phase analysis with facility to omit or consider graphite nodules

#### **b. Gray Cast Iron by ASTM A247**

Class separation (A, B, C & D type) of flakes as per ASTM A 247 and estimation of percentage of each class

Size classification as per ASTM A247

Identification of largest flake in the field of view and reporting the respective size class

### **B.5 Aluminum and alloys Analysis**

Percentage porosity estimation

Geometrical parameters such as length, diameter, perimeter estimation of Silicon cuboid particles

Dendritic Arm Spacing estimation

### **B.6 Banding Analysis as per ASTM E1268**

Anisotropy Index and Degree of Orientation estimation

Thickness of banding and inter-band spacing measurement

### **B.7 Decarburization depth Analysis**

Facility for tracing decarb interface and selection of number of readings for better averaging

### **B.8 2D analysis of features of interest as per following**

Object counting

Distance between any two points

Angle between any two edges

Area Measurement

Circle - radius, perimeter, circularity percentage measurement Rectangle measurement

Irregular shape measurement

### **B.9 Additional features**

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All the results can be reported in units like micron, mm, cm, inch etc.  
Quick Calibration attachment system with freedom for adding additional magnifications  
Special software for Database compilation and comparison

#### **B.10 Planar Stitching in X and Y direction**

One can stitch multiple images captured randomly in X and Y directions to offer complete presentation of interested area in single frame

#### **B.11 Z stacking / Extended depth of focus**

Obtaining Fully focused image by smart image blending of partially focused images captured at different Z planes.

#### **B.12 Batch Run**

Swift Batch Run (processing batch of images in one go) for effective and faster processing of large number of images captured.  
This module can be effectively used in Grain Size Analysis, Phase Analysis, Inclusion Analysis, Nodularity and graphite Flake Analysis.  
Analyzing parameter can be navigated image by image in case user want to fine tune them for any particular image.

#### **B.13 Motorized Stage operating and programming software**

XYZ movement control of stage from PC

#### **B.14 Report generation in MS-Excel format**

#### **B.15 Calibration - Traceable to NPL, Delhi/CMTI Bangalore**

#### **B.16 Desktop Computer**

Processor - Intel® Core™ i5, Memory - 4 GB, Hard-drive - 1 TB, Graphic card, 18.5" LED Screen, keyboard, mouse, Deskjet Printer, UPS 0.5KVA

**OR**  
**Equivalent**

  
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